

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/579,911 | Applicant(s)/Patent Under Reexamination HANZAWA ET AL. | |
| | Examiner FERNANDO N. HIDALGO | Art Unit 2827 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|--|-----------------|------|----------------|
| | A US- | | | |
| | B US- | | | |
| | C US- | | | |
| | D US- | | | |
| | E US- | | | |
| | F US- | | | |
| | G US- | | | |
| | H US- | | | |
| | I US- | | | |
| | J US- | | | |
| | K US- | | | |
| | L US- | | | |
| | M US- | | | |

FOREIGN PATENT DOCUMENTS

| * | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|--|-----------------|---------|------|----------------|
| | N | | | | |
| | O | | | | |
| | P | | | | |
| | Q | | | | |
| | R | | | | |
| | S | | | | |
| | T | | | | |

NON-PATENT DOCUMENTS

| * | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|
| U | Johns et al., Analog Integrated Circuit Design, 1997, John Wiley & Sons, Inc., page 94. |
| V | |
| W | |
| X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.